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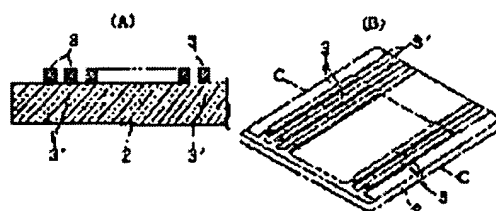
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(54) PROBE UNIT AND MANUFACTURE THEREOF

(57)Abstract:

PURPOSE: To obtain a probe unit provided with resilient contact pieces by projecting the end part of a lead group arranged at a fine pitch on the surface of a base board from the base board in which the lead group can be formed soundly and easily without requiring the work for bonding the lead group to the base board.

CONSTITUTION: A large number of leads 3 are grown by plating on the surface of a base board 2 and a resilient contact piece 3a is formed at one end of the lead 3 projected from one end of the base board 2. First and second base boards are then abutted each other on the end faces thereof and a large number of leads are grown by plating on the surface of the first and second base boards while traversing both base boards and being arranged side by side. Finally, the second base board is stripped and the lead terminals extending on the second base board are projected from the end part of the first base board.



LEGAL STATUS

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